Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/652,137	ESSICK ET AL.	
Examiner ,	Art Unit	
Denise Tran	2185	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
711/202,206-207; 710/305- 306,314(text search only, search history printout)	7/24/2006	DT	
inventor name seach	7/24/2006	DT	
East (USPGPUB;USPAT; USOCR; EPOAB; JPOAB; DERWENT, IBM- TDB)	7/24/2006	DT	
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